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Editorial Office

Instytut Fizyki Politechniki Wrocławskiej
Wybrzeże Wyspiańskiego 27, 50-370
Wrocław, Poland

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In addition to larger original papers brief reports will be published of the authors' own research work. The report should be set out according to the above guide lines.

The Editorial Board invites the readers to send over any remarks or observations referring to the publications which will appear in the *Optica Applicata*. The correspondence of essential importance will be published in a separate column dealing with letters to the Editor.

Review of Matter

Application of the diffraction theory, quantum optics, problems in radiation coherence, light sources, holography and its application, scientific photography, methods of image reconstruction, optical application of Fourier transforms, theory of optical systems, criteria of optical image evaluation, optical materials, technology of manufacturing optical elements, aspheric optics, optical properties of solids and thin films, lasers and their application, photo- and radiometry, problems in spectroscopy, non-linear optics, optical data processing, optical measurements, fibre optics, optical instrumentation, interferometry, microscopy, non-visible optics, automation of optical computing, optoelectronics, colorimetry, optical detectors, elipsometry and photoelasticity.

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